TOSHIBA Transistor Silicon NPN Epitaxial Type

# 2SC6079

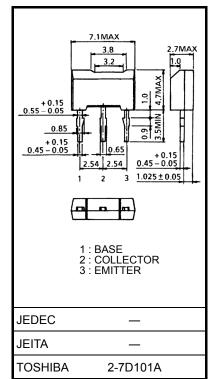
### Power Amplifier Applications Power Switching Applications

Low collector saturation voltage: VCE (sat) = 0.5 V (max)  $\rm (IC$  = 1A) High-speed switching:  $t_{stg}$  = 0.4  $\mu s$  (typ)

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#### Absolute Maximum Ratings (Ta = 25°C)

Characteristic	Symbol	Rating	Unit	
Collector-base voltage		V <sub>CBO</sub>	160	V
Collector-emitter voltage		V <sub>CEX</sub>	160	V
Collector-emitter voltage		V <sub>CEO</sub>	80	V
Emitter-base voltage		V <sub>EBO</sub>	9	V
Collector current	DC	Ι <sub>C</sub>	2.0	А
	Pulse	I <sub>CP</sub>	4.0	А
Base current		Ι <sub>Β</sub>	1.5	А
Collector power dissipation		PC	1	W
Junction temperature		Tj	150	°C
Storage temperature range		T <sub>stg</sub>	-55~150	°C



Weight:0.2g(typ)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

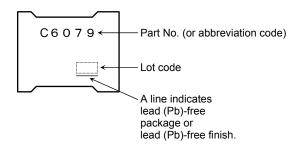
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Unit: mm

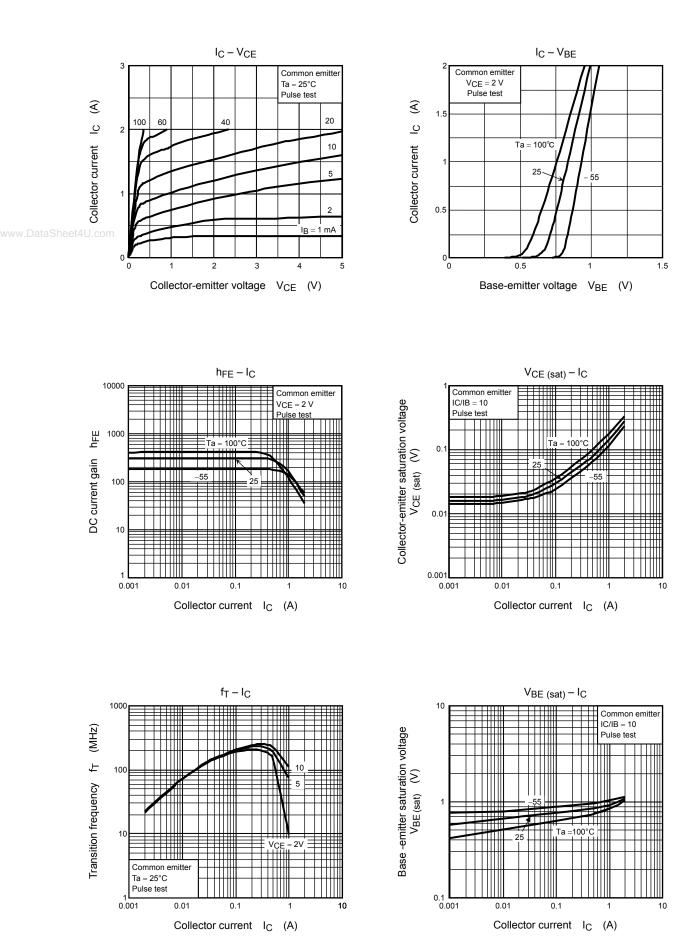
Electrical Characteristics (Ta = 25°C)

	Charae	cteristic	Symbol	Test Conditions	Min	Тур.	Max	Unit
	Collector cut-off current		I <sub>CBO</sub>	V <sub>CB</sub> = 160 V, I <sub>E</sub> = 0	_	_	1.0	μA
	Emitter cut-off current		I <sub>EBO</sub>	V <sub>EB</sub> = 9 V, I <sub>C</sub> = 0			1.0	μA
	Collector-emitter breakdown voltage		V (BR) CEO	I <sub>C</sub> = 10 mA, I <sub>B</sub> = 0	80	_	_	V
	DC current gain		h <sub>FE (1)</sub>	V <sub>CE</sub> = 2 V, I <sub>C</sub> = 1 mA	150	_	_	
			h <sub>FE (2)</sub>	V <sub>CE</sub> = 2 V, I <sub>C</sub> = 0.5 A	180	_	450	
et4 L <u>com</u> Base-er Transitio Collecto			h <sub>FE (3)</sub>	V <sub>CE</sub> = 2 V, I <sub>C</sub> = 1 A	100	_	_	
	Collector emitter saturation voltage		V <sub>CE (sat) (1)</sub>	I <sub>C</sub> = 0.5 A, I <sub>B</sub> = 50 mA	_	_	0.3	V
			V <sub>CE (sat) (2)</sub>	I <sub>C</sub> = 1 A, I <sub>B</sub> = 100 mA	_	_	0.5	V
	Base-emitter saturation voltage		V <sub>BE (sat)</sub>	I <sub>C</sub> = 1 A, I <sub>B</sub> = 100 mA	_	_	1.5	V
	Transition frequency		fT	V <sub>CE</sub> = 2 V, I <sub>C</sub> = 0.5 A	_	150	_	MHZ
	Collector output capacitance		C <sub>ob</sub>	V <sub>CB</sub> = 10 V, I <sub>E</sub> = 0,f = 1MH <sub>Z</sub>	_	14	_	pF
		Rise time	tr	$20 \ \mu s$ $Input$ $I$	_	0.05	_	
	Switching time	Storage time	t <sub>stg</sub>		_	0.4	_	μS
		Fall time	t <sub>f</sub>		_	0.15	_	

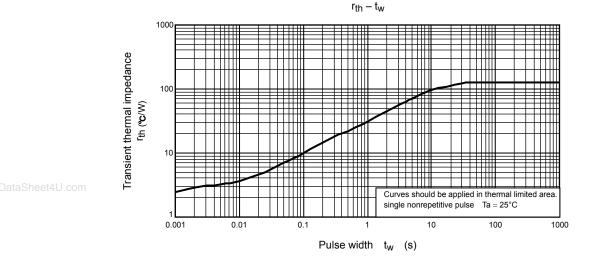
## Marking



## TOSHIBA



# <u>TOSHIBA</u>



Safe Operating Area 10 IC max. (pulsed)\* 1 ms\* +++++IC max. (continuous) 10 ms 1111 Æ 00 m -DC operation Ta=25°C <u>ں</u> Collector current 0.1 0.01 \* Single nonrepetitive pulse Ta = 25°C Curves must be derated linearly with increase in temperature. VCEO MAX. 0.001 0.01 0.1 10 100 1 Collector–emitter voltage  $V_{CE}$  (V)

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